



US00D923500S

(12) **United States Design Patent**
Jiang

(10) **Patent No.:** **US D923,500 S**

(45) **Date of Patent:** **** Jun. 29, 2021**

(54) **MULTIMETER**

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(**) Term: **15 Years**

(21) Appl. No.: **29/719,801**

(22) Filed: **Jan. 8, 2020**

(51) **LOC (13) Cl.** **10-05**

(52) **U.S. Cl.**
USPC **D10/78**

(58) **Field of Classification Search**

USPC D10/46, 61, 70-80, 52, 53, 65, 69;
324/114, 127, 126, 149, 115, 508, 133,
324/156, 556, 555, 72.5
CPC G01R 15/186; G01R 15/18; G01R 1/00;
G01R 1/22; G01R 1/20; G01R 31/041;
G01R 31/67; G01R 31/50; G01R 31/04;
G01R 31/02; G01R 31/52; G01R 31/54;
G01R 19/145; G01R 31/69; G01R
1/06788; G01R 31/024; G01R 15/125;
G01R 1/04; G01R 19/2509; G01R 13/02;
G01R 1/025; G01D 18/008; G01D 11/24;
G01K 15/005; H04L 67/303; H04L
67/12; G05B 19/0426; G05B 2219/25428;
G08C 17/02; H04B 10/11; H04B 10/114;
G01C 15/004; G01C 15/00; G01C
15/002; G01C 15/06; G01B 11/26; G02B
7/001; Y10T 29/49826; H04Q 2209/40
See application file for complete search history.

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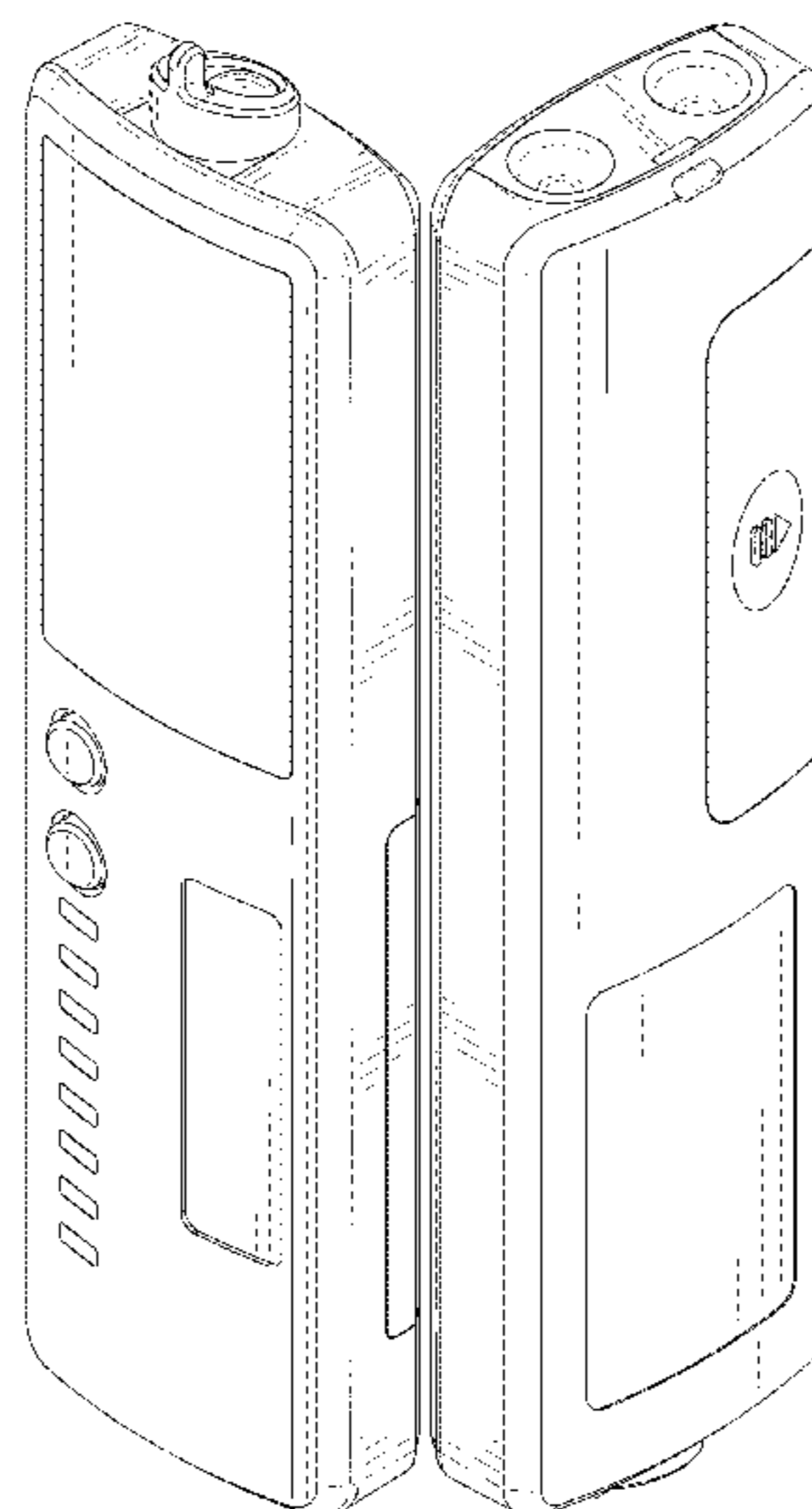
(57) **CLAIM**

The ornamental design for a multimeter, as shown and described.

DESCRIPTION

FIG. 1 is a front and top perspective view of a multimeter, showing my new design;
FIG. 2 is a rear and bottom perspective view thereof;
FIG. 3 is a front elevational view thereof;
FIG. 4 is a rear elevational view thereof;
FIG. 5 is a left side elevational view thereof;
FIG. 6 is a right side elevational view thereof;
FIG. 7 is a top plan view thereof; and,
FIG. 8 is a bottom plan view thereof.
The broken lines in the figures illustrate portions of the multimeter that form no part of the claimed design.

1 Claim, 8 Drawing Sheets



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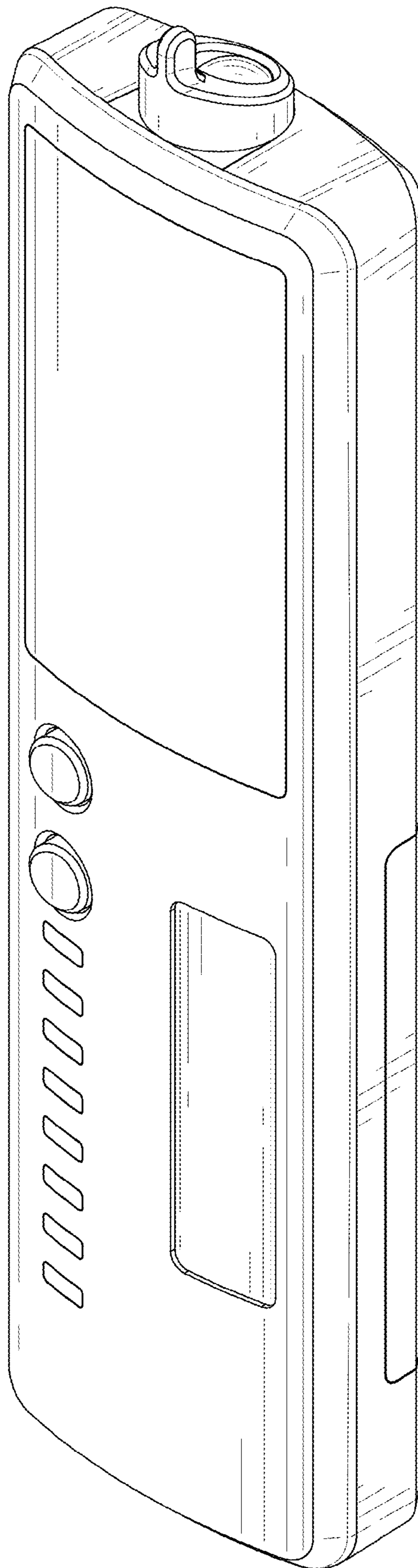


FIG. 1

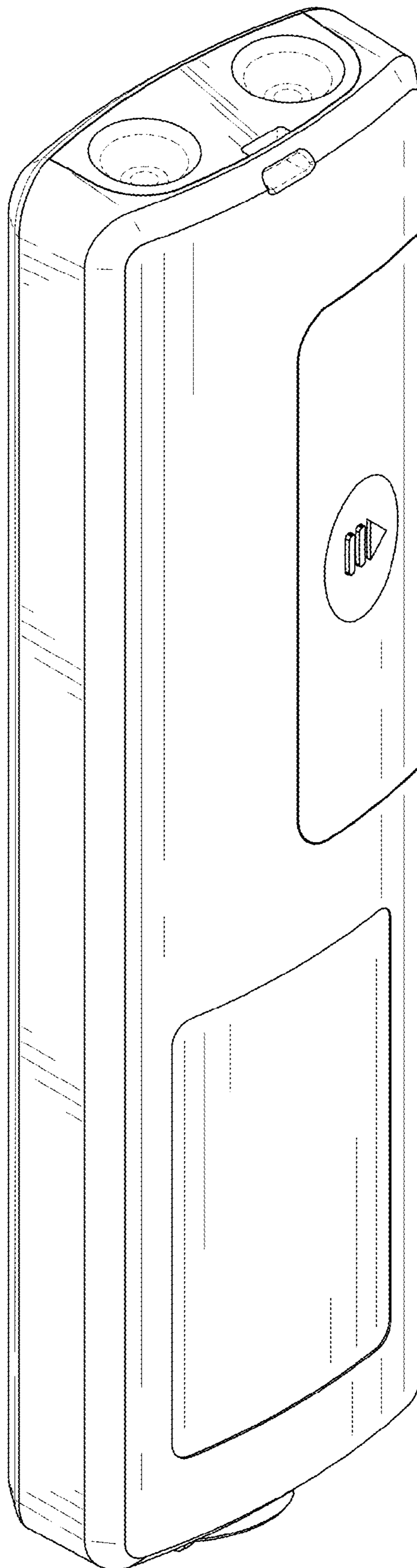


FIG. 2

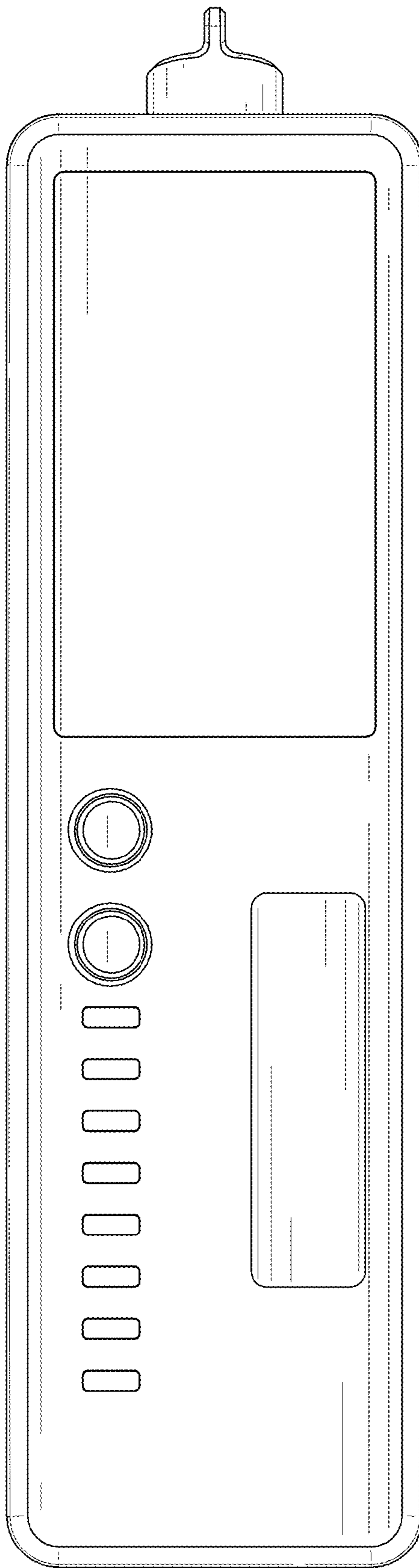


FIG. 3

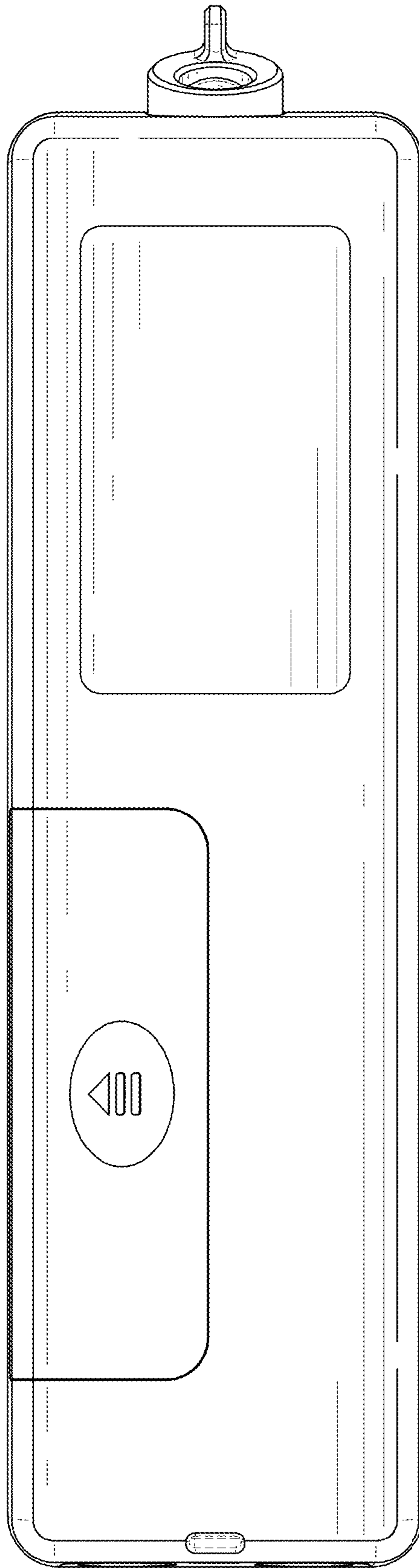


FIG. 4

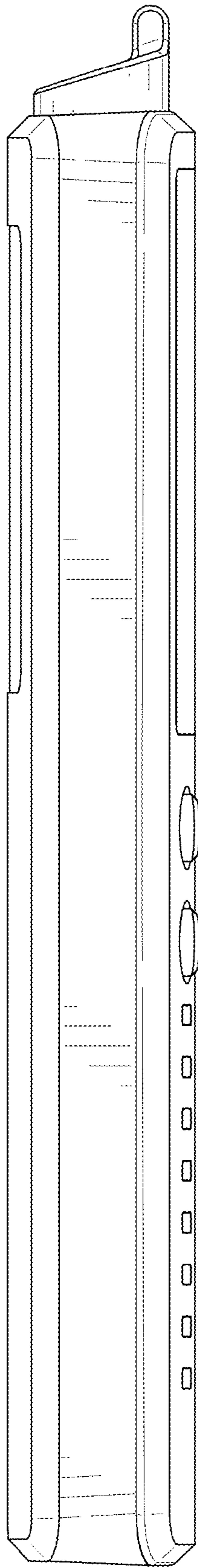


FIG. 5

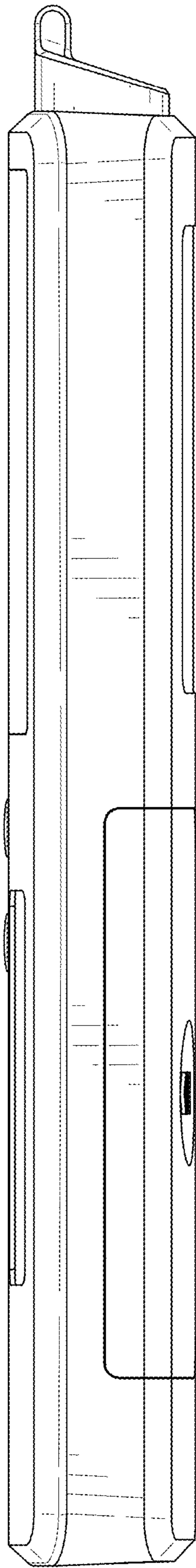


FIG. 6

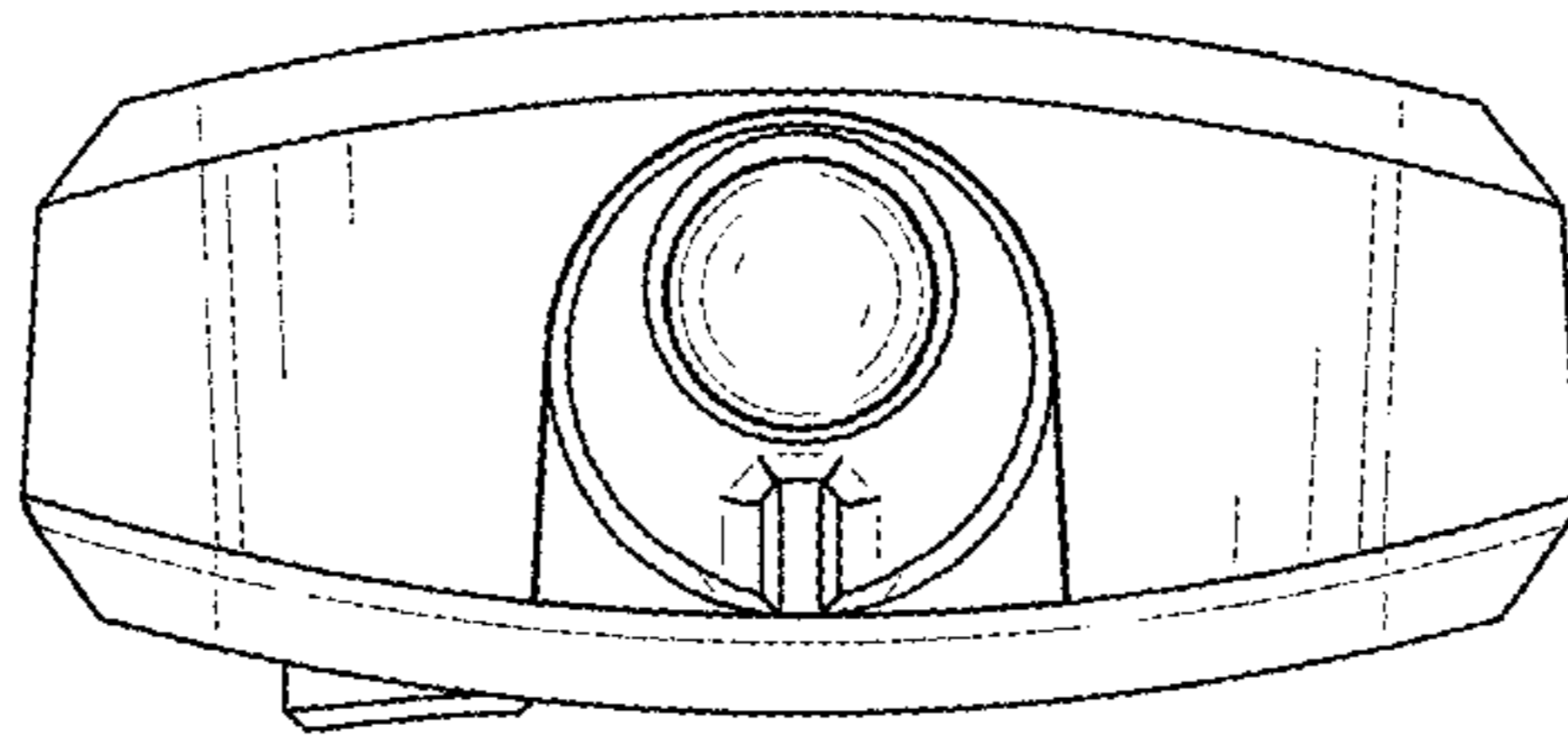


FIG. 7

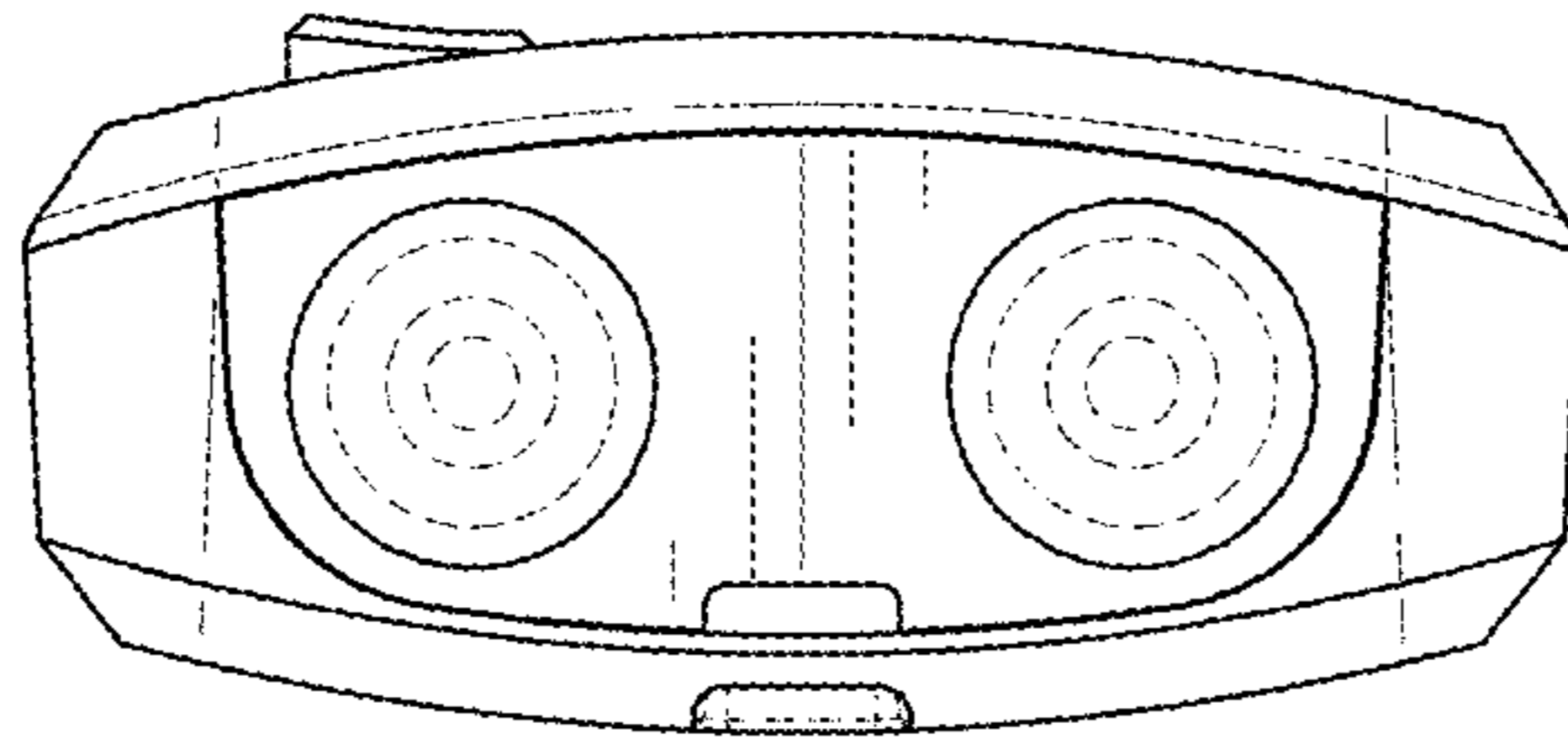


FIG. 8